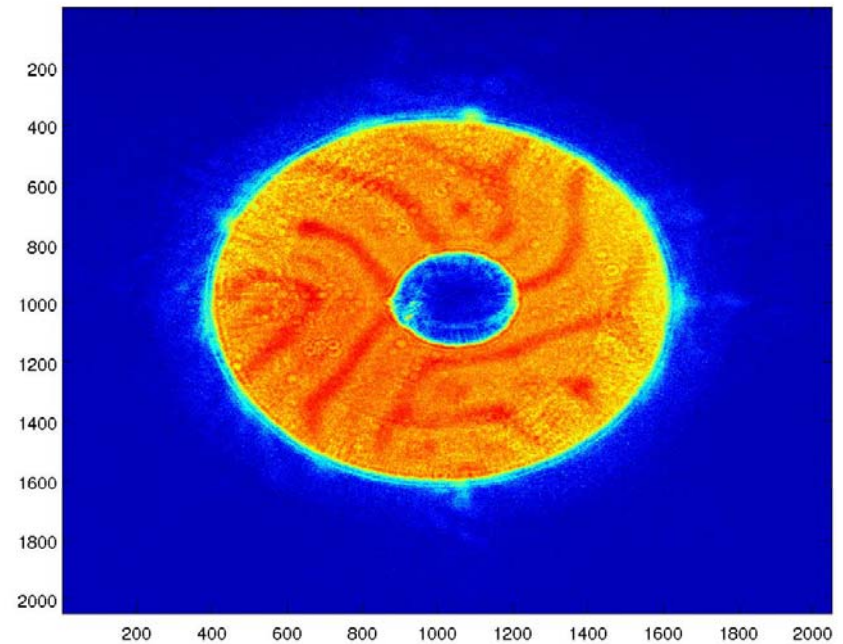
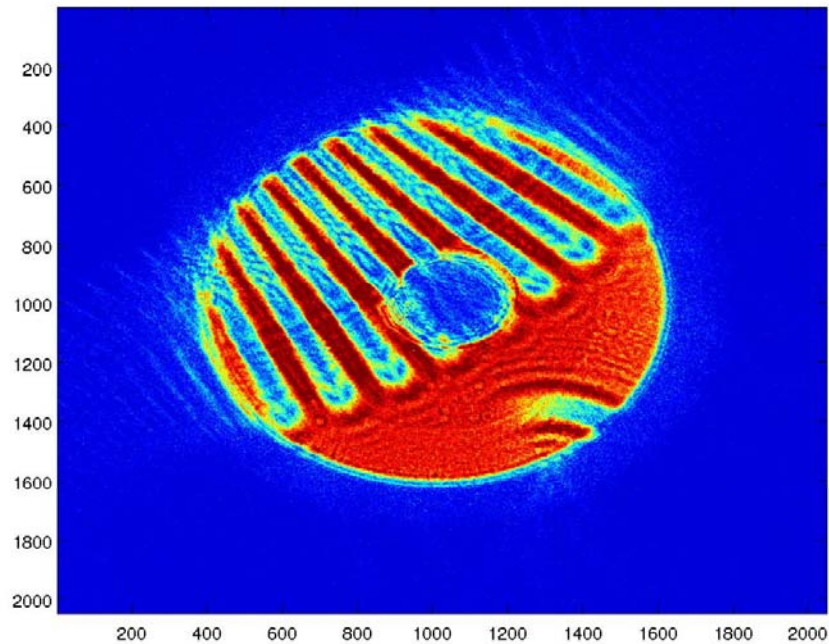


# Ptychographical Fresnel Coherent Diffractive Imaging

Sebastian Dietze

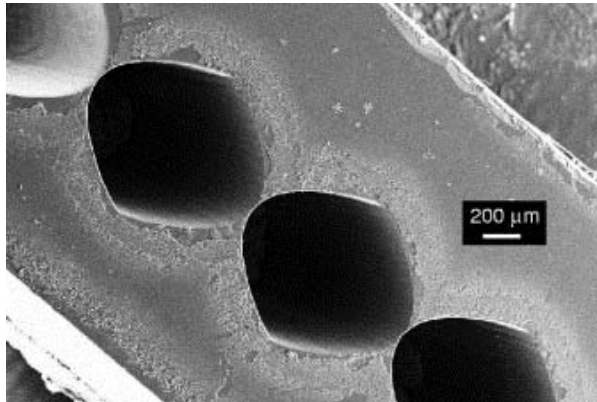


# Outline

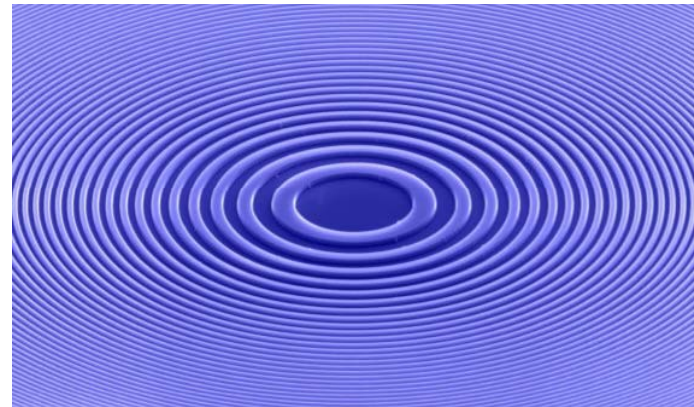
- Why go lensless?
- Coherent Diffraction Imaging (CDI) phase retrieval Techniques
- Fresnel Keyhole Method
- Combining FCDI and PIE

# Limitations of Focusing Optics

- Fabrication Limits
  - Aberrations, Cost, Efficiency
- Practical Limits
  - Alignment, Degradation

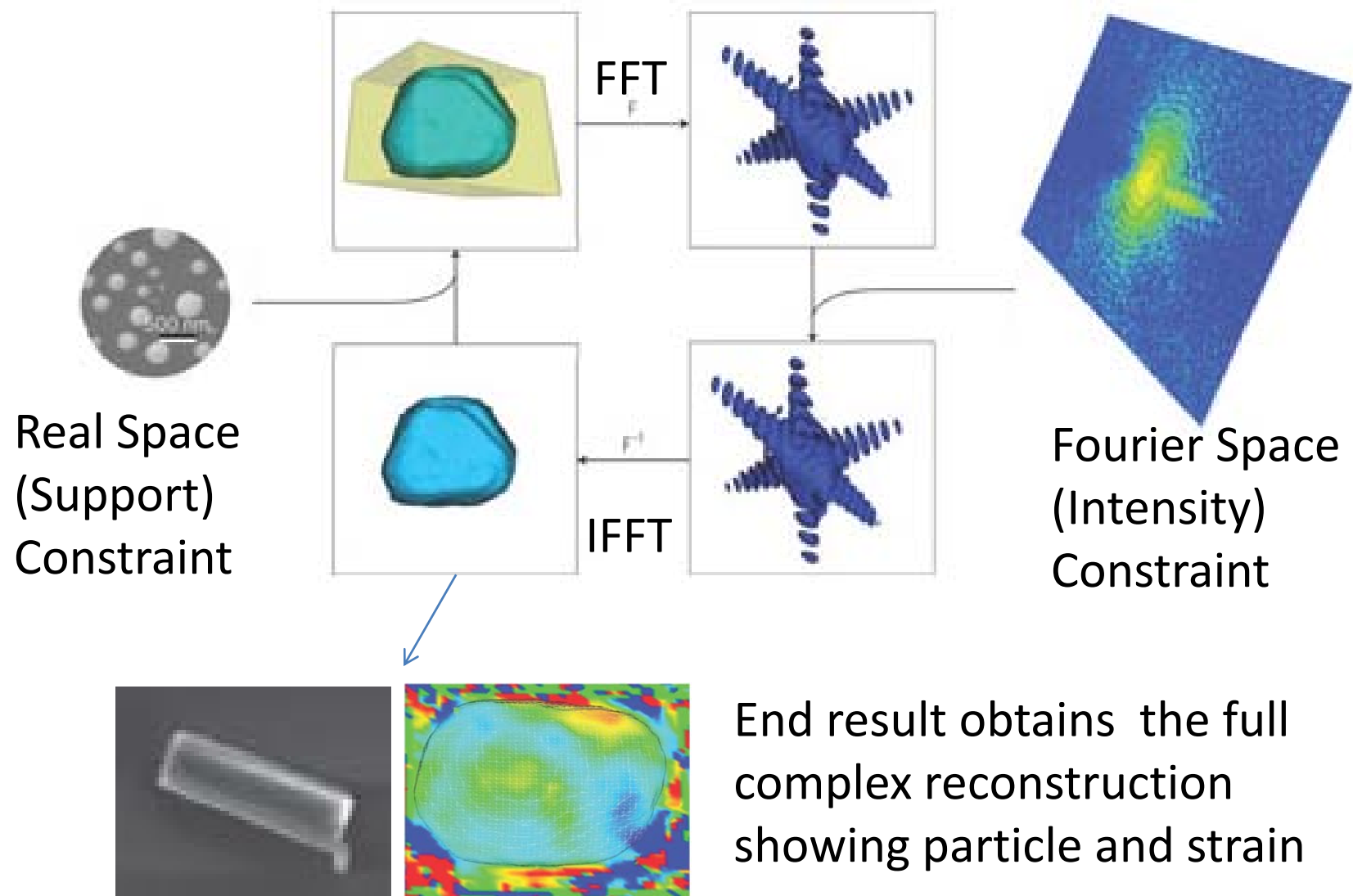


Parabolic Planar Compound Lens  
A. Artemiev. NIMPRA. **543** 322 (2005)



Silicon Fresnel zone plates for high heat load.  
J. Vila-Comamala. Micr Eng **85** No. 5-6 (2008)

# HIO Phase Retrieval Algorithm

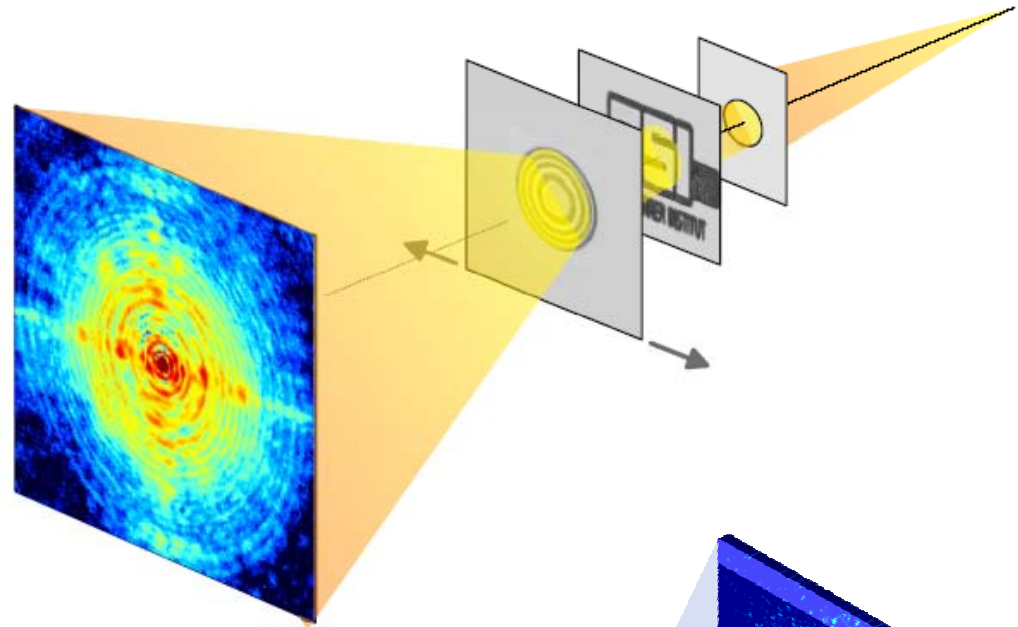


I. Robinson, R. Harder. Nature Materials 8, 291 (2009)

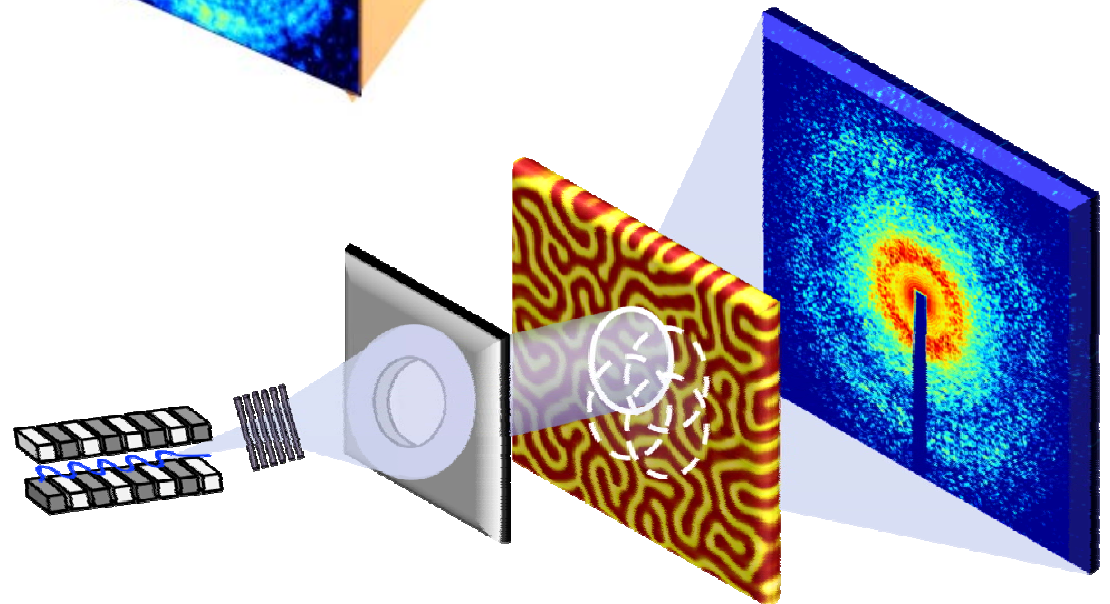
# Complimentary Images

Phase Shift:  
Multiple exposures  
with phase shifted  
wave front.

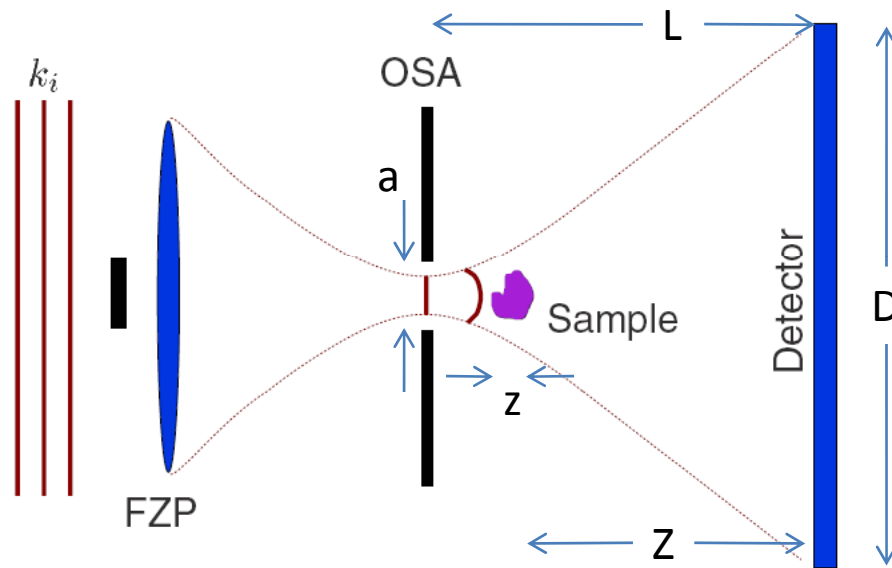
I. Johnson et al. PRL **100**  
155503 (2008)



Ptychography :  
Multiple exposures  
with significant  
overlapping region



# Fresnel Imaging



G. Williams. PRL **97** 025506 (2006)

Required Conditions

Far Field:  $Z \gg D$

Thin sample:  $z \ll Z$

Alternatively,

$$\frac{a^2}{\lambda L} \approx 1 \quad \lambda \ll L$$

Resolution will be wavelength limited, not FZP resolution limited

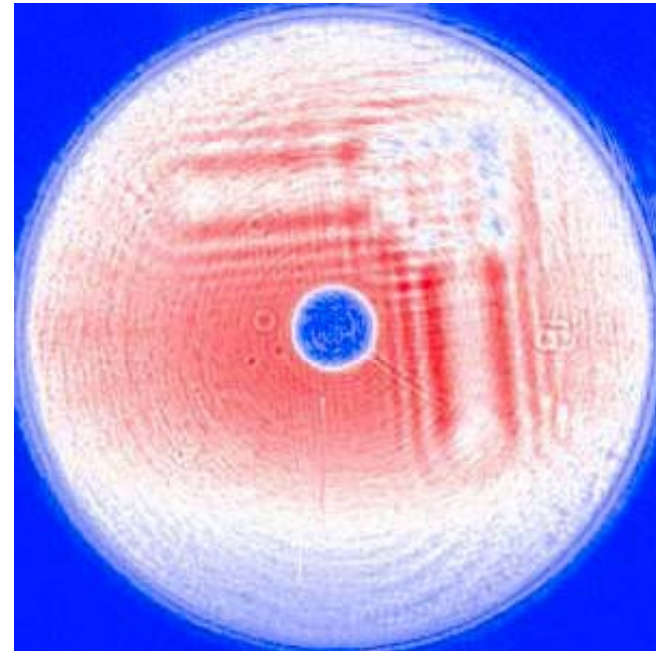
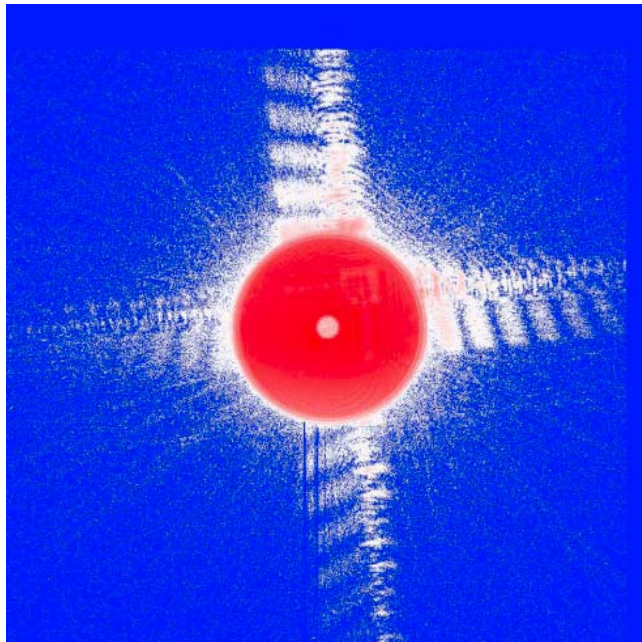
$$F_s(\mathbf{R}) = \frac{1}{Z} e^{ikz} \int d^2r s(\mathbf{r}) \Psi(\mathbf{r}) e^{i\frac{k\rho^2}{2Z}} = FrT2D\{s(\mathbf{r})\} \quad \boldsymbol{\rho} = \mathbf{R} - \mathbf{r}$$

$$F_t(\mathbf{R}) = t \left( \frac{L-Z}{L} \mathbf{R} \right) \Psi(\mathbf{R})$$

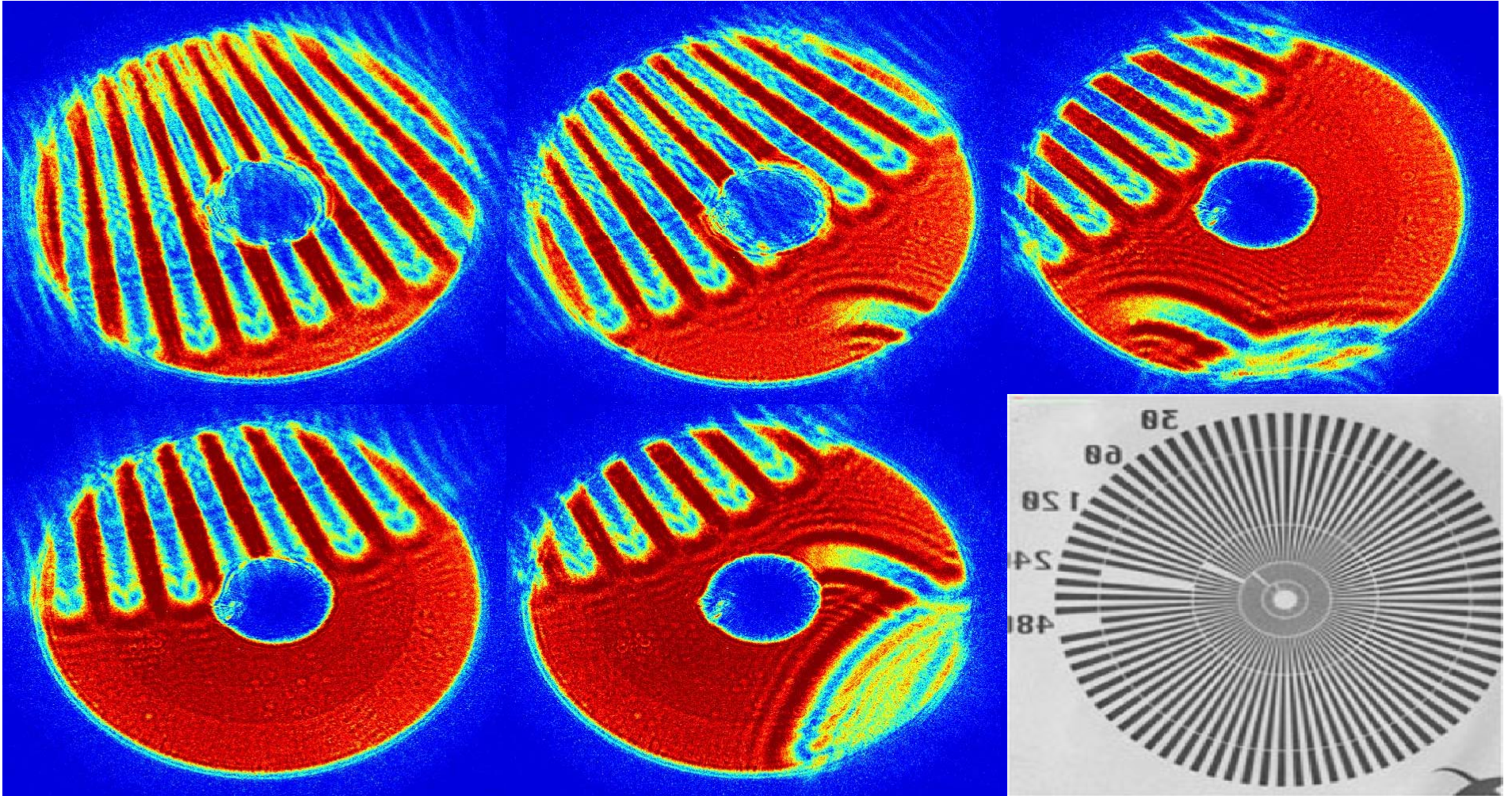
$\mathbf{R}$  is vector in detector plane and  $\mathbf{r}$  is vector in sample x-y plane

# Keyhole

The central region is an in-line hologram using a curved wave front. Propagate back to sample plane to obtain additional real space constraint for phase retrieval algorithm.

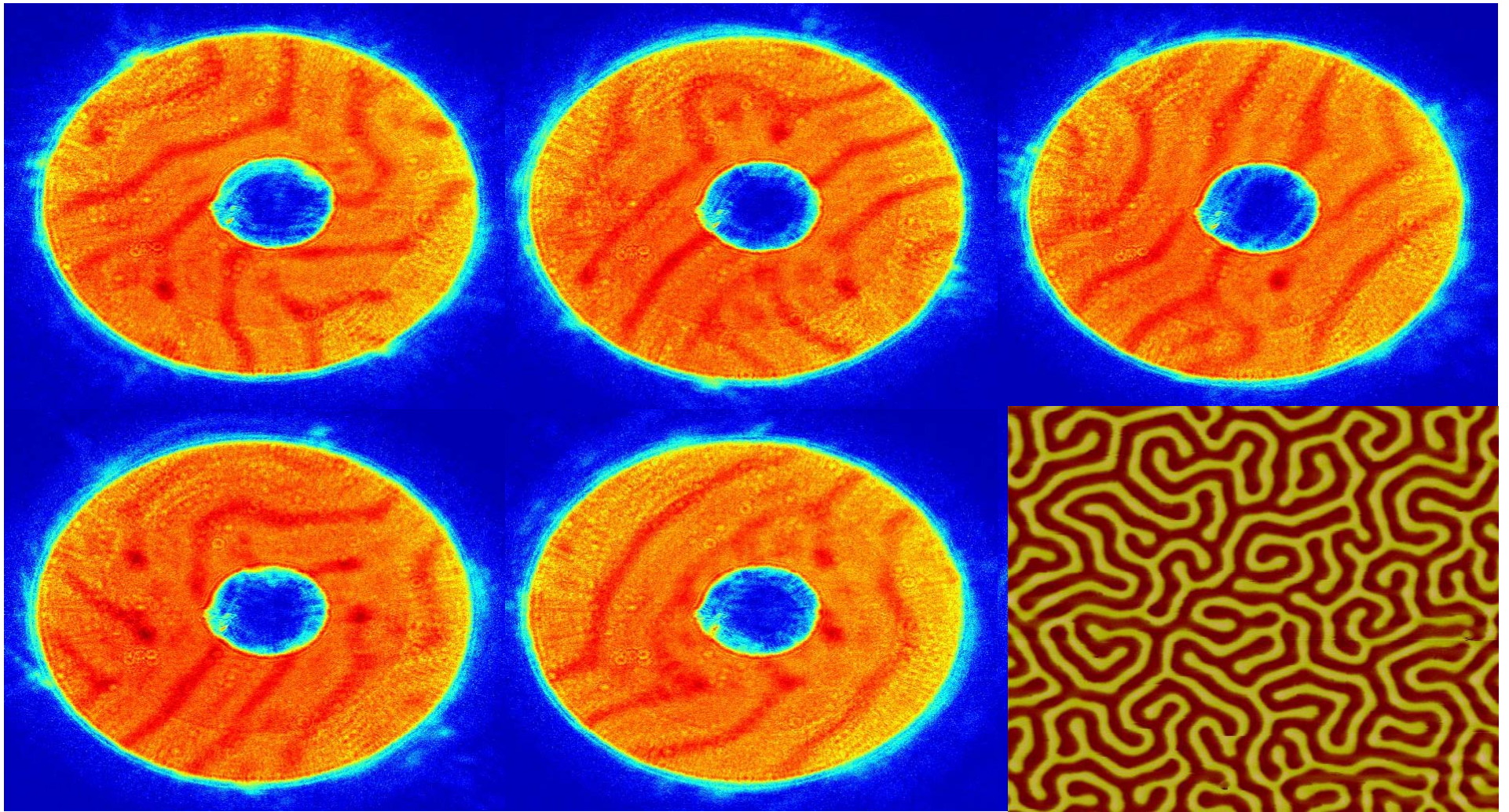


# PFCDI on AU Test Pattern

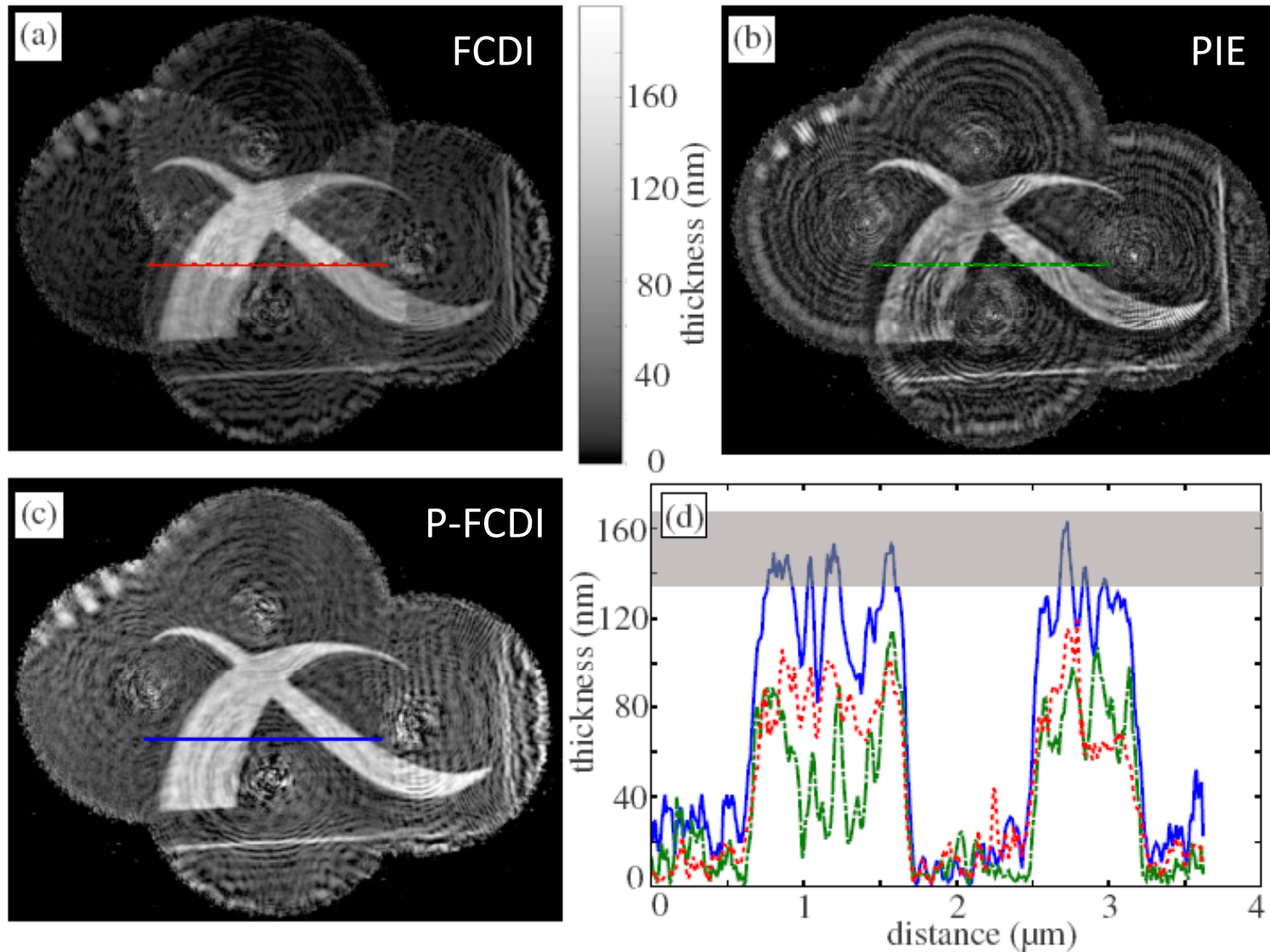




# PFCDI on GdFe Stack



# Comparison of Reconstruction



D. Vine et al. Phys Rev A **80** 063823 (2009)

# Azimuthal Symmetry in 2D Diffraction in Fraunhofer regime using Elastic Scattering

For thin films, can use a 2D FT of scattering density to obtain diffraction pattern

$$F(\mathbf{q}_{\perp}) = FT2D\{f(\mathbf{x}_{\perp})\} = \int d\mathbf{x}_{\perp} f(\mathbf{x}_{\perp}) e^{i\mathbf{q}_{\perp} \cdot \mathbf{x}_{\perp}}$$

The complimentary point is at

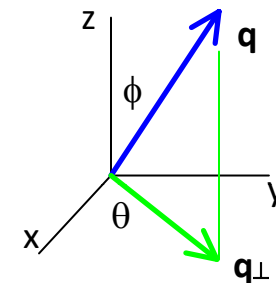
$$\phi' = \phi \quad \theta' = \theta + \pi \quad \longrightarrow \quad \mathbf{q}'_{\perp} = -\mathbf{q}_{\perp}$$

The C.C. of FT2D at complimentary pt is,

$$F^*(\mathbf{q}'_{\perp}) = \int d\mathbf{x}_{\perp} f^*(\mathbf{x}_{\perp}) e^{i\mathbf{q}_{\perp} \cdot \mathbf{x}_{\perp}}$$

Therefore if  $f(x)$  is real, the intensities are equal.

$$I(\mathbf{q}'_{\perp}) = |F(\mathbf{q}'_{\perp})|^2 = I(\mathbf{q}_{\perp})$$



$$\mathbf{q}_{\perp} = \frac{2\pi}{\lambda} (a\hat{x} + b\hat{y})$$

$$a = \sin(\phi) \cos(\theta)$$

$$b = \sin(\phi) \sin(\theta)$$

# Diffraction; Contrast Mechanism

$$O_{\pm}(\mathbf{r}) = e^{-\mu_0 t} e^{\pm m_z(\mathbf{r}) \mu_c t} = e^{-\mu_0 t} [\cosh(m_z(\mathbf{r}) \mu_c t) \pm \sinh(m_z(\mathbf{r}) \mu_c t)],$$

$$\begin{aligned} I &= \frac{I_+ + I_-}{2} = \frac{1}{2} [|\text{FT}\{P(\mathbf{r})O_+(\mathbf{r})\}|^2 + |\text{FT}\{P(\mathbf{r})O_-(\mathbf{r})\}|^2] \\ &= e^{-2\mu_0 t} \left[ |\text{FT}\{P(\mathbf{r}) \cosh(m_z(\mathbf{r}) \mu_c t)\}|^2 \right. \\ &\quad \left. + |\text{FT}\{P(\mathbf{r}) \sinh(m_z(\mathbf{r}) \mu_c t)\}|^2 \right]. \end{aligned}$$

$$\begin{aligned} I &= e^{-2\mu_0 t} \left[ |\text{FT}\{P(\mathbf{r})\}|^2 \right. \\ &\quad \left. + (\mu_c t)^2 |\text{FT}\{P(\mathbf{r})m_z(\mathbf{r})\}|^2 \right. \\ &\quad \left. + \frac{1}{2} (\text{FT}\{P(\mathbf{r})\}^* \text{FT}\{P(\mathbf{r})m_z^2(\mathbf{r})\} + \text{C. C.}) \right] + \mathcal{O}\{(\mu_c t)^4\}. \end{aligned}$$

$$I \approx e^{-2\mu_0 t} \left[ |\text{FT}\{P(\mathbf{r})\}|^2 + (\mu_c t)^2 |\text{FT}\{P(\mathbf{r})m_z(\mathbf{r})\}|^2 \right].$$

A. Tripathi et al. (2010)

